

Application/Control No. 10/046,926	Applicant(s)/Patent undo Reexamination TEIG ET AL.	er
Examiner	Art Unit	•
Vuthe Siek	2825	

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(Assi	(Assistant Examiner) (Date) VUT					IH- SIEK		G29/06_	Total Claims Allowed: 12					
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								60B,63						

Claims renumbered in the same order as presented by applicant								☐ CPA			☐ T.D.			☐ R.1.47					
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